U.S. Serial No. 10/564,742

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

n re patent application of: Daisuke ENDO, et al.

Serial No.: 10/564,742

Group Art Unit: 1729

Filing Date: January 17, 2006

Examiner: Jacob B. Marks

For:

POSITIVE ACTIVE MATERIAL, PROCESS FOR PRODUCING THE SAME, AND POSITIVE ELECTRODE FOR LITHIUM SECONDARY BATTERY AND

LITHIUM SECONDARY BATTERY EACH EMPLOYING THE SAME

Honorable Commissioner for Patents Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Under the provisions of 37 CFR §1.97 through §1.98 and pursuant to applicants' duty of disclosure under 37 CFR §1.56, applicants respectfully bring the following documents cited in the Japanese Office Action dated September 6, 2011 in a counterpart foreign application and listed on the attached form PTO-1449, to the attention of the Examiner in charge of the above-identified application. Copies of the listed documents are provided herewith for the convenience of the Examiner (with English abstracts). Further, an English language translation of the Office Action is attached.

In compliance with the requirements of 37 CFR §1.98(a)(3), as a concise statement of relevance, as it is presently understood by the individual designated in 35 U.S.C. §1.56(c) most knowledgeable about the content of the information, the undersigned attorney of record submits a translation of portions of an official action by a foreign examiner in which the references were cited. The relevance to the pending U.S. patent application is that the references were cited in a foreign patent application on the same subject matter. However, no independent analysis of the reference, the accuracy of the statement of the foreign examiner or the claims of the foreign application under the laws of that country or the United States relative to the subject matter claimed in the present application has been made, the present understanding of the contents thereof by the undersigned being based on the translation of the foreign examiner's comments submitted herewith.

I hereby certify that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement.

This citation does not constitute an admission that the references are relevant or material to the claims. They are only cited as constituting related art of which the applicant is aware.

It is respectfully requested that the listed references be considered by the Examiner and formally made of record in this application.

Please charge any deficiencies in fees and credit any overpayment of fees to Attorney's Deposit Account No. 50-0481.

Respectfully submitted,

Farhad Shir, Ph.D. Registration No. 59,403

Sean M. McGinn, Esq. Registration No. 34,386

McGinn Intellectual Property Law Group, PLLC Intellectual Property Law

Intellectual Property Law 8321 Old Courthouse Road, Suite 200 Vienna, VA 22182-3817 (703) 761-4100

Customer No. 21254

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Form PTO-A820 (also form PTO-1449)

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